

Sunday, June 29

1:00	18:00	Registration	Sheraton – Fireplace Room
18:30	20:00	Welcome Reception	Sheraton - South Atrium

Monday, June 30

7:30	Continental Breakfast		Sheraton - Pre-function Area		
8:00	12:00	Late Registration	Fireplace Room		
8:00	Welcome and Conference Opening – B. Doyle, J. Phillips		Sheraton Conference Center – Rooms EFGH		
8:30		Joseph Sanchez – “ <i>The Spanish Presence in North America: Or do you know the way to Santa Fe?</i> ”			
		Plenary Talks; Chair: G. Vizkelethy			
9:00	MON-PLE-1	<i>The Role of Ion Beam Analysis in the Determination of the Structure & Composition of Oxides</i> – I. Vickridge			
9:30	MON-PLE-2	<i>Ion Beam Analysis for Future Electronic Device & Process Development</i> – M. Takai			
10:00		BREAK	<i>Pre-function area</i>		
	Invited & Contributed Sessions				
	Materials Science 1 (oxides); Chair: L. Feldman - Conference Center E		Nuclear Microscopy; Chair: P. Rossi – Conference Center FGH		
10:30	MON-AM-A-1	<i>Using IBA in Determining the Mechanisms of Cleavage in Hydrogen Ion Implanted Si</i> – M. Nastasi	10:30	MON-AM-B-1	<i>IBA Using a Microprobe of 17 MeV Protons & High Energy Heavy Ions</i> – P. Reichart
11:00	MON-AM-A-2	<i>Study of Thin Hafnium Oxides Films Deposited by Atomic Layer Deposition</i> – J. Ganem	11:00	MON-AM-B-2	<i>Focusing of MeV Ion Beams by Tapered Glass Capillaries & Its Application to Material Analysis</i> – T. Narusawa
11:20	MON-AM-A-3	<i>Degradation of SiO₂ Films Under 1 MeV/amu Heavy Ion Irradiation</i> – W. Arnoldbik	11:20	MON-AM-B-3	<i>Magnetic Sextuplet as a Zoom Lens for the Nuclear Microprobe at the Louisiana Accelerator Center</i> – A. Dymnikov
11:40	MON-AM-A-4	<i>ERDA Study of Hydrogen Trapping at the Hf_xSi_{1-x}O₂/Si Interface</i> - M. El Bouanani	11:40	MON-AM-B-4	<i>Three-dimensional Ion Microbeam Tomography of Pearlescent Pigments</i> – J. Simcic
12:00		LUNCH (your own arrangements)			
13:30	Poster Session 1		Conference Center ABCD, Potters, Weavers, Turquoise rooms		
15:00		BREAK	Pre-function area		
	Materials Science 2; Chair: H. Karl – Conference Center E		Single Ion Techniques & Applications; Chair: M. Jaksic - Conference Center FGH		
15:30	MON-PM-A-1	<i>Virtues & Pitfalls in Structural Analysis of Ion Implanted Heterostructures by the Complementary Use of RBS/ channeling & High Resolution X-ray Diffraction</i> – A. Turos	15:30	MON-PM-B-1	<i>Development of Single Ion Hit Techniques & Their Applications at TIARA of JAERI Takasaki</i> – T. Kamiya
15:50	MON-PM-A-2	<i>IBA: A Toolkit for Storage Technology R&D</i> – A. Kellock	16:00	MON-PM-B-2	<i>Ion-Induced Emission Microscopy for IBA</i> – P. Rossi
16:10	MON-PM-A-3	<i>Ion Beam Induced Phase Transformation Detection by Ion Beam Induced Luminescence</i> – G. Gosnell	16:30	MON-PM-B-3	<i>Theory of Ion Beam Induced Charge Collection in Semiconductor Devices Based on the Gunn’s Theorem</i> – E. Vittone
16:30	MON-PM-A-4	<i>Lattice Location of Mn & Fundamental Curie Temperature Limit in Ferromagnetic Ga_{1-x}Mn_xAs</i> – K. Yu	16:50	MON-PM-B-4	<i>Inspection of Floating Body Effects in SOI Devices Using High Energy Nuclear Microprobes</i> – S. Abo
16:50	MON-PM-A-5	<i>Helium Retention in As-Implanted Silicon</i> – P. Fichtner	17:10	MON-PM-B-5	<i>Investigation of Intra-crystallite Charge Transport in CVD Diamond with Ion Beam Induced Charge Imaging</i> – A. Simon
17:10	MON-PM-A-6	<i>Annealing Behavior of Al-Implantation-Induced Disorder in 4H-SiC</i> – Y. Zhang			
18:00		DINNER (your own arrangements)			
19:30	Workshops		Conference Center E, FGH & Franciscan Room		
22:00	Daily Session Concludes				

Tuesday, July 1

7:30	Continental Breakfast		Pre-function Area		
		Plenary Talks; Chair: J. Tesmer	Conference Center EFGH		
8:30	TUE-PLE-1	<i>Ion Energy Loss: Mechanisms & Models</i> – G. Schiwietz			
9:00	TUE-PLE-2	<i>Materials Characterization Needs in the Metrology Roadmap</i> – A. Diebold			
9:30	TUE-PLE-3	<i>High Resolution RBS: A Powerful Tool for Atomic Level Characterization</i> – K. Kimura			
10:00		BREAK	Pre-function area		
	High Resolution; Chair: R. Elliman - Conference Center E		Materials Science 3 (channeling); Chair: A. Pathak – Conf Center FGH		
10:30	TUE-AM-A-1	<i>Ultra High Resolution IBA</i> – G. Dollinger	10:30	TUE-AM-B-1	<i>Assessment of Subsurface Damage in II-VI Semiconductors by Ion Channeling</i> – D. Lucca
11:00	TUE-AM-A-2	<i>Heavy Ion Elastic Recoil Detection Analysis of Silicon-rich Silica Films</i> – T. Weijers	11:00	TUE-AM-B-2	<i>Channeling Study of the Damage Induced in Ceramic Oxide Crystals Irradiated with High-energy Heavy Ions</i> – L. Thomé
11:20	TUE-AM-A-3	<i>RBS with High Depth Resolution Using a Small Magnetic Spectrometer</i> – R. Grötzschel	11:20	TUE-AM-B-3	<i>Structural Characterization of Half-metallic Heusler Compound NiMnSb: a New Material for Spintronics</i> – L. Nowicki
11:40	TUE-AM-A-4	<i>Reliable ERD Analysis of Group-III Nitrides Despite Severe Nitrogen Depletion Due to Electronic Energy Loss</i> – S. Shrestha	11:40	TUE-AM-B-4	<i>The Unique Role of IBA in Modeling the Thermal Evolution of Hydrogen in Si Implanted at Doses Required for Ion Cutting</i> – O. Holland
12:00		LUNCH (your own arrangements)			
13:30	Poster Session 2		Conference Center ABCD, Potters, Weavers, Turquoise rooms		
15:00		BREAK	Pre-function area		
	Fundamentals 1; Chair: G. Schiwietz - Conference Center E		Hardware Techniques; Chair: G. Norton - Conference Center FGH		
15:30	TUE-PM-A-1	<i>SRIM – The Stopping & Range of Ions in Matter</i> – J. Ziegler	15:30	TUE-PM-B-1	<i>Compact AMS Facilities: Recent Developments & Prospects</i> – M. Suter
16:00	TUE-PM-A-2	<i>Paradoxical Features of Angular Multiple Scattering in Matter & Their Implications in Depth Profiling with IBA</i> – G. Amsel	16:00	TUE-PM-B-2	<i>A New Time-of-flight Instrument for Quantitative Surface Analysis</i> – I. Veryovkin
16:30	TUE-PM-A-3	<i>Stopping of Light & Heavy Ions</i> – P. Sigmund	16:20	TUE-PM-B-3	<i>AMS Depth Profiling of Tritium in Carbon & Humidity in Silica</i> – M. Friedrich
17:00	TUE-PM-A-4	<i>Elastic Recoil Detection Analysis of He-3</i> – J. Knapp	16:40	TUE-PM-B-4	<i>Gas Ionization Chambers with Silicon Nitride Windows for the Detection & Identification of Low-Energy Ions</i> – M. Döbeli
17:20	TUE-PM-A-5	<i>Z₁ & Position Dependence of Channeling Stopping Power</i> – A. Pathak	17:00	TUE-PM-B-5	<i>A Nanosecond Pulsing System for MeV Light Ions Using a 2 Mv Tandetron</i> – D. Mous
Bohmische Physical Society					
18:30	Reception		Pre-function Area		
19:30	Meeting		Conference Center EFGH		

22:00 Daily Session Concludes

Wednesday, July 2

7:30	Continental Breakfast	Pre-function Area
	Plenary Talks; Chair: H. Schone	Conference Center EFGH
8:30	WED-PLE-1	<i>Developments in Proton Beam Writing</i> – F. Watt
9:00	WED-PLE-2	<i>Medium Energy Ion Scattering Spectroscopy for Interface Composition & Structure Analysis</i> – D. Moon
9:30	WED-PLE-3	<i>Ion Beam Analysis for Fusion Energy Research</i> – W. Wampler
10:00	<i>BREAK</i>	<i>Pre-function area</i>
10:30	Poster Session 1	Conference Center ABCD, Potters, Weavers, Turquoise rooms
12:00	Conference Outing (includes lunch)	Buses depart in front of the Sheraton
18:30		Buses return to the Sheraton
18:30	<i>DINNER</i> (<i>your own arrangements</i>)	
19:00	International Committee Meeting	
22:00	Daily Session Concludes	

Thursday, July 3

7:30	Continental Breakfast		Pre-function Area		
		Plenary Talks; Chair: G. Bench	Conference Center EFGH		
8:30	THU-PLE-1	<i>Ion Beam Bio-inorganic Elemental Microanalysis: Applications for Investigation of Normal & Pathological Nerve Cell Function</i> – K. Briski			
9:00	THU-PLE-2	<i>Ion Beam Analysis for Single Atom Doping</i> – D. Jamieson			
9:30	THU-PLE-3	<i>Data Analysis of Elastic Scattering Spectrometry</i> – E. Rauhala			
10:00		BREAK	Pre-function area		
	Data Analysis; Chair: J. Knapp - Conference Center E		Bio-Medical/Earth; Chair: A. Sjoland – Conf Center FGH		
10:30	THU-AM-A-1	<i>Monte Carlo Simulations of Surface Roughness Effects in ERD Measurements</i> – K. Arstila	10:30	THU-AM-B-1	<i>Quantifying & Characterizing Proteins with MeV Ions</i> – P. Grant
11:00	THU-AM-A-2	<i>Efficient Monte Carlo Simulation of Heavy Ion Elastic Recoil Detection Analysis Spectra</i> – R. Franich	11:00	THU-AM-B-2	<i>Elemental Microanalysis in Ecophysiology Using Ion Microbeam</i> – W. Przybylowicz
11:20	THU-AM-A-3	<i>A General Artificial Neural Network for Analysis of RBS Data of any Element with Z between 18 & 83 Implanted into any Lighter One- or Two-element Target</i> – N. Barradas	11:20	THU-AM-B-3	<i>Single Ion Bombardment of Living Cells at LIPSION</i> – T. Reinert
11:40	THU-AM-A-4	<i>High-energy PIXE: Quantitative Analysis</i> – A. Denker (<u>P1-21 in the abstract book</u>)	11:40	THU-AM-B-4	<i>Nuclear Microprobe Analysis of Volatile Elements in a Chondritic Meteorite</i> – C. Wetteland
12:00		LUNCH (your own arrangements)			
	High Sensitivity; Chair: C. Wetteland - Conference Center E		Materials Science 4; Chair: W. Jiang- Conference Center FGH		
13:30	THU-PM-A-1	<i>Heavy Ion Backscattering Spectrometry at the University of Central Florida</i> – G. Braunstein	13:30	THU-PM-B-1	<i>Applications of Nuclear Reactions in Addressing Environmental & Industrial Material Issues</i> – S. Thevuthasan
14:00	THU-PM-A-2	<i>Measurement of Very Low Bulk Concentrations (below 1 ppm) of Hydrogen Using ERDA</i> – A. Tripathi	14:00	THU-PM-B-2	<i>Corrosion Studies by IBA Techniques</i> – R. Hanrahan
14:20	THU-PM-A-3	<i>ERD, ¹⁵N NRRA in Air, HIRBS: IBA Developments on the Good Old EN-1</i> – F. Schiettekatte	14:20	THU-PM-B-3	<i>Thermal Oxidation of 6H SiC Studied by Oxygen Isotopic Tracing & Narrow Nuclear Resonance Profiling</i> – I. Trimaille
14:40	THU-PM-A-4	<i>H⁺, H₂⁺ and H₃⁺ Induced X-rays in Si Under Channeling Conditions</i> – M. Behar	14:40	THU-PM-B-4	<i>Measurements of He-3 Retention in Tungsten, Simulating Conditions at the First Wall of an IFE Reactor, Using He-3(d,p) He-4 Nuclear Reaction Analysis</i> – S. Gilliam
15:00		BREAK	Pre-function area		
15:30	Poster Session 2		Conference Center ABCD, Potters, Weavers, Turquoise rooms		
Conference Reception and Banquet					
18:30	Reception		Pre-function area		
19:30	Banquet		Conference Center EFGH		

22:00 Daily Session Concludes

Friday, July 4

7:30	Continental Breakfast		Pre-function Area		
		Plenary Talks; Chair: S. Thevuthasan	Conference Center EFGH		
8:30	FRI-PLE-1	<i>Ion Beam Analysis in Art & Archaeology: Attacking the Precision Power Paradigm</i> – M. Abraham			
9:00	FRI-PLE-2	<i>Ion Beam Microanalysis in Geoscience Research</i> – C. Ryan			
9:30	FRI-PLE-3	<i>The Use of Ion Beams in Nanoscience & Nanotechnologies Research</i> – J. Barbour			
10:00		BREAK	<i>Pre-function area</i>		
	Art/Archaeology; Chair: B. Wilkens - Conference Center E		Environmental Science; Chair: C. Ryan – Conf Center FGH		
10:30	FRI-AM-A-1	<i>IBA of Art Works: 14 Years of Use in the Louvre</i> – J. Dran	10:30	FRI-AM-B-1	<i>IBA Methods for Characterization of Fine Particulate Atmospheric Pollution: A Local, Regional & Global Research Problem</i> – D. Cohen
11:00	FRI-AM-A-2	<i>Characterization of Early Medieval Paintings by Micro-PIXE, SEM & Raman Spectroscopy</i> – A. Zucchiatti	11:00	FRI-AM-B-2	<i>Application of Accelerator SIMS in Environmental Sciences</i> – C. Maden
11:20	FRI-AM-A-3	<i>The Non-destructive Appraisal of Early Chinese Porcelain by PIXE</i> – H. Cheng	11:20	FRI-AM-B-3	<i>Size & Time Resolved Atmospheric Aerosol & Radionuclide Measurements Using Ion Beams & Radionuclide Aerosol Sampler/Analyzer: Rattlesnake Mountain Study 2002</i> – V. Shutthanandan
11:40	FRI-AM-A-4	<i>In-air PIXE Setup for Automatic Analysis of Historical Documents Inks</i> – M. Budnar	11:40	FRI-AM-B-4	<i>Lattice Location of Helium in Uranium Dioxide Single Crystals</i> – L. Nowicki
12:00		LUNCH (your own arrangements)			
	Sputtering Physics; Chair: D. McDaniel - Conference Center E		Low/Medium Energy; Chair: D. Moon - Conference Center FGH		
13:30	FRI-PM-A-1	<i>Existence of Transient Temperature Spike Induced by SHI: Evidence by IBA</i> – D. Avasthi	13:30	FRI-PM-B-1	<i>MEIS Studies of the Composition & Breakup of Ultrathin High-k Dielectrics</i> – T. Gustafsson
14:00	FRI-PM-A-2	<i>ERDA & Electronic Sputtering</i> – W. Assmann	14:00	FRI-PM-B-2	<i>Development of Medium-energy Ion Scattering Microscopy</i> – T. Kobayashi
14:30	FRI-PM-A-3	<i>Open Questions in Electronic Sputtering of Solids by Slow, Very Highly Charged Ions</i> – T. Schenkel	14:20	FRI-PM-B-3	<i>Depth Characterization of nm-Layers by Low Energy Ion Scattering</i> – M. Draxler
			14:40	FRI-PM-B-4	<i>A Combined LEIS/STM Study of Two Types of Surface Reconstruction of Magnetic Fe4N Layers</i> – R. Gonzáles-Arrabal
15:00		BREAK	<i>Pre-function area</i>		
15:30	Concluding Remarks / Conference Closing				